



BSI Standards Publication

Semiconductor devices — Guidelines for reliability qualification plans

Part 2: Concept of mission profile

National foreword

This British Standard is the UK implementation of EN IEC 63287-2:2023. It is identical to IEC 63287-2:2023.

The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors.

A list of organizations represented on this committee can be obtained on request to its committee manager.

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